RF EXPOSURE REPORT FOR CERTIFICATION On Behalf of

Lucent Trans Electronics Co., Ltd

Dual Wireless Charging Pad

Model Number: WC10WDUALGGL-AL

Additional Model: WC10WDUALGGLWH-AL, 7WH

FCC ID: UQ3DUAL10W

Prepared for:	Lucent Trans Electronics Co., Ltd				
	9F-1, No. 16, Chien Pah Rd., Chung Ho Dist., New Taipei City, Taiwan				
Prepared By:	EST Technology Co., Ltd.				
	Chilingxiang, Qishantou, Santun, Houjie, Dongguan, Guangdong, China				
Tel: 86-769-83081888-808					

Report Number:	ESTE-R2003002
Date of Test:	Feb. 19~Mar. 28, 2020
Date of Report:	Mar. 02, 2020



TABLE OF CONTENTS

<u>Descri</u>	ption		<u>Page</u>
TEST RI	- EPORT	VERIFICATION	3
1.	Sum	MARY OF TEST	4
	1.1.	Summary of test result	4
	1.2.	Test Mode	4
	1.3.	Test Equipment List	4
2.	MAX	KIMUM PERMISSIBLE EXPOSURE	5
		Limit	
	2.2.	Test Setup A	6
	2.3.	Test Setup B	6
	2.4.	Equipment Approval Considerations	7
	2.5.	Test Result for Test setup A:	7
	2.6.	Test Result for Test setup B:	8
3.		T SETUP PHOTOT	



EST Technology Co., Ltd.

	EST Techn	ology Co., Ltd	I.
Applicant: Address:	Lucent Trans Electronics C 9F-1, No. 16, Chien Pah Ro	and the same of th	New Taipei City,Taiwan
Manufacturer: Address:	Lucent Trans Electronics C 9F-1, No. 16, Chien Pah Ro		New Taipei City,Taiwan
E.U.T:	Dual Wireless Charging Pa	nd	
Model Number:	WC10WDUALGGL-AL		
Additional Model:	WC10WDUALGGLWH-A		
Power Supply:	DC 5V From Adapter Input DC 9V From Adapter Input DC 12V From Adapter Input DC 15V From Adapter Input	AC 100-240V, 50- at AC 100-240V, 50	60Hz 0-60Hz
Trade Name:	Verizon	Serial No.:	
Date of Receipt:	Feb. 19, 2020	Date of Test:	Feb. 19~Feb. 28, 2020
Test Specification:	FCC Part 15 Subpart C ANSI C63.10:2013		
Test Result:	Ltd. was assumed full resp measurements. Also, this re with the FCC Rules and Re	contained in this test on sibility for the acceport shows that the egulations Part 15 Set tested sample only	st report and EST Technology Co., curacy and completeness of these EUT to be technically compliance subpart C requirements. y and shall not be reproduced in
			Date: Mar. 02, 2020
Prepared by:	Reviewed by	:	Approved by:
Ring	Shawr	1	They the
Ring. Yang / Assista	Shawn.Xiao / Er	ngineer	Iceman Hu / Manager
Other Aspects: None.			Chorize
Abbreviations: OK/P=pas	ssed fail/F=failed n.a/N=	not applicable E.U	J.T=equipment under tested

1. SUMMARY OF TEST

1.1. Summary of test result

Report Section	Description of Test Item	FCC Standard Section	Results
3	Maximum Permissible Exposure	Part 1.1307(b)&1.1310	PASS

1.2. Test Mode

Mode	Description	
	Full Load	
Charging mode with dummy load	Half Load	
	Empty Load	

1.3. Test Equipment List

Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
Exposure Level Tester	Narda	ELT-400	EST-E105	Aug. 21,19	1 Year
B-Field Probe	Narda	ELT Probe	EST-E106	Aug. 30,19	1 Year



EST Technology Co., Ltd Report No. ESTE-R2003002 Page 4 of 14

2. MAXIMUM PERMISSIBLE EXPOSURE

2.1. Limit

Limits for Maximum Permissible Exposure (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm2)	Averaging time (minutes)
	(A) Limits for (Occupational/Contr	rolled Exposure	
0.3-3.0	614	1.63	*100	6
3.0-30	1842/f	4.89/f	*900/f ²	6
30-300	61.4	0.163	1.0	6
300-1,500			f/300	6
1,500-100,000			5	6
	(B) Limits for Gene	ral Population/Unc	controlled Exposure	ę
0.3-1.34	614	1.63	*100	30
1.34-30	824/f	2.19/f	*180/f ²	30
30-300	27.5	0.073	0.2	30
300-1,500			f/1500	30
1,500-100,000			1.0	30

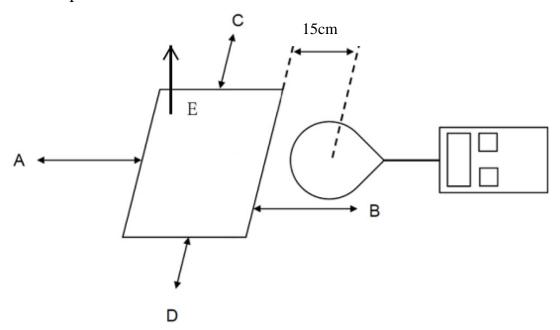
Note:

- 1. f = frequency in MHz * = Plane-wave equivalent power density.
- 2. For devices designed for typical desktop applications, such a wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 15 cm. E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 15 cm measured from the center of the probe(s) to the edge of the device. Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m. A KDB inquiry is required to determine the applicable exposure limits below 100 kHz.

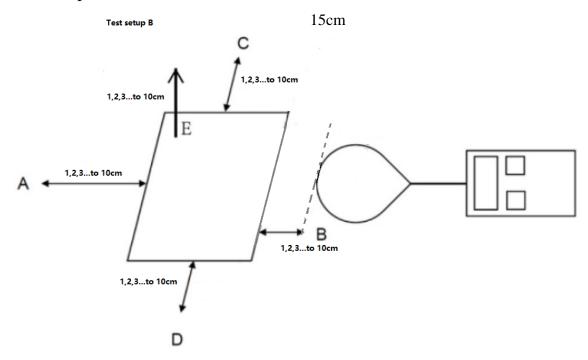


EST Technology Co., Ltd Report No. ESTE-R2003002 Page 5 of 14

2.2. Test Setup A



2.3. Test Setup B



- a. The test was performed on 360 degree turn table in anechoic chamber.
- b. The probe was placed at 15 cm surrounding the device and 20 cm above the top of the charger and the geometric centre of the probe, for test setup A.
- c. Measure magnetic and electrical field strength at a distance 10cm to 1cm at 1cm iteration, Which is between the edge of the charger and the edge of of probe, for test setup B.
- d. The highest emission level was recorded and compared with limit as soon as measurement of each point; A, B, C, D, E were completed.
- e. The EUT was measured according to the dictates of KDB680106D01v03;



 EST Technology Co., Ltd

2.4. Equipment Approval Considerations

Inductive wireless power transfer applications with supporting field strength results and meeting all of the following requirements are not required to submit a KDB inquiry for devices approved using SDoC or a PAG for equipment approved using certification to address RF exposure compliance.

1	Power transfer frequency is less that 1 MHz
	YES; the device operated in the frequency range from 110.5-205KHz.
2	Output power from each primary coil is less than or equal to 15 watts.
	NO; the maximum output power of the primary coil is 20W.
3	The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.
	YES
4	Client device is placed directly in contact with the transmitter.
	YES; Client device is placed directly in contact with the transmitter.
5	Mobile exposure conditions only (portable exposure conditions are not covered by
	this exclusion).
	YES
6	The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the
	top surface from all simultaneous transmitting coils are demonstrated to be less than
	50% of the MPE limit.
	YES; The EUT field strength levels are 50% x MPE limts.

2.5. Test Result for Test setup A:

E-field strength					
Frequency range (KHz)		110.5 to 205			
Test Mode	Full Load	Half Load	Empty Load		
Position A(V/m)	2.202	1.625	1.057		
Position B(V/m)	2.325	1.709	1.224		
Position C(V/m)	2.219	1.653	1.111		
Position D(V/m)	2.328	1.805	1.269		
Position E(V/m)	2.209	1.531	1.189		
Limits (V/m) 614					
50% Limits(V/m)	307				

H-field strength						
Frequency range (KHz)		110.5 to 205				
Test Mode	Full Load	Half Load	Empty Load			
Position A(A/m)	0.496	0.365	0.216			
Position B(A/m)	0.491	0.343	0.223			
Position C(A/m)	0.433	0.330	0.231			
Position D(A/m)	0.438	0.331	0.226			
Position E(A/m)	0.449	0.388	0.225			
Limits (A/m)		1.630				
50% Limits (A/m)		0.815				



EST Technology Co., Ltd Report No. ESTE-R2003002 Page 7 of 14

2.6. Test Result for Test setup B:

Empty, Half, Full load all have been tested, only worse case Max load (Full) is reported.

E-Filed Strength at (distance 10cm to 1cm at 1cm iteration, i.e. at a distance of 10cm, 9cm, 8cm, 1cm, Which is between the edge of the charger and the edge of of probe,) surrounding the EUT (V/m)

Test distance (cm)	Position A (V/m)	Position B (V/m)	Position C (V/m)	Position D (V/m)	Position E (V/m)	Limits (V/m)
1	7.691	7.655	7.523	7.661	7.654	614
2	7.016	7.013	6.991	6.897	7.021	614
3	6.451	6.511	6.525	6.559	6.531	614
4	6.121	6.045	6.061	5.988	6.118	614
5	5.661	5.553	5.613	5.661	5.651	614
6	5.129	5.031	5.154	5.091	5.144	614
7	4.631	4.709	4.589	4.559	4.609	614
8	4.250	4.354	4.331	4.258	4.325	614
9	3.794	3.691	3.707	3.721	3.691	614
10	3.326	3.289	3.355	3.401	3.407	614

H-Filed Strength at (distance 10cm to 1cm at 1cm iteration, i.e. at a distance of 10cm, 9cm, 8cm, 1cm, Which is between the edge of the charger and the edge of of probe,) surrounding the EUT (A/m)

Test distance (cm)	Position A (A/m)	Position B (A/m)	Position C (A/m)	Position D (A/m)	Position E (A/m)	Limits (A/m)
1	0.709	0.697	0.696	0.708	0.704	1.63
2	0.691	0.685	0.684	0.685	0.683	1.63
3	0.675	0.671	0.679	0.681	0.665	1.63
4	0.661	0.665	0.665	0.661	0.658	1.63
5	0.653	0.659	0.651	0.655	0.643	1.63
6	0.641	0.634	0.631	0.639	0.636	1.63
7	0.623	0.625	0.625	0.625	0.615	1.63
8	0.609	0.611	0.599	0.597	0.613	1.63
9	0.595	0.594	0.587	0.590	0.605	1.63
10	0.588	0.581	0.581	0.575	0.584	1.63

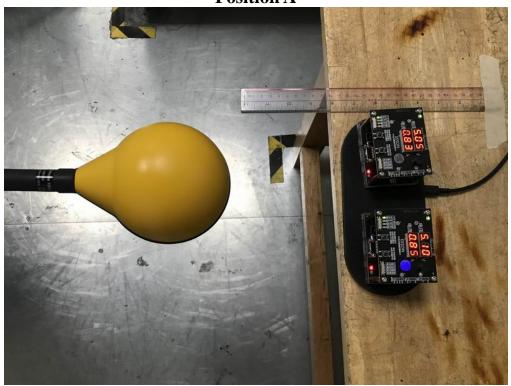


EST Technology Co., Ltd Report No. ESTE-R2003002

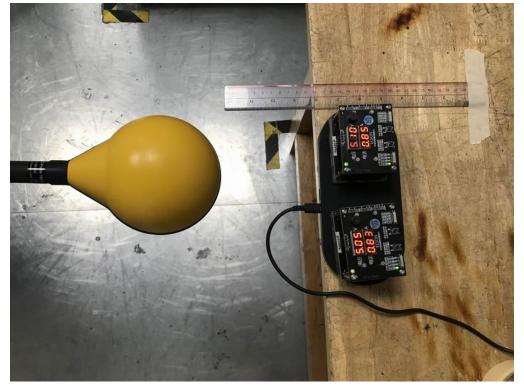
3. TEST SETUP PHOTO

Test setup B



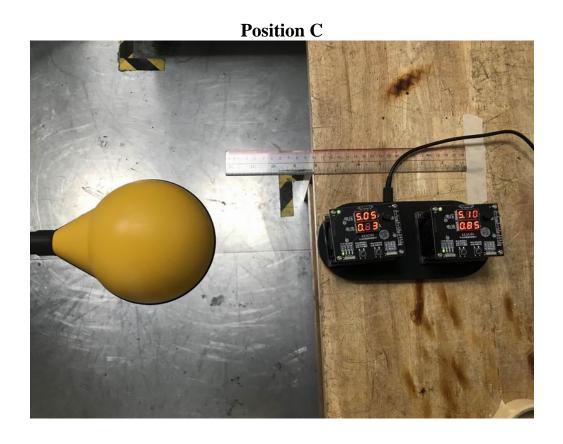


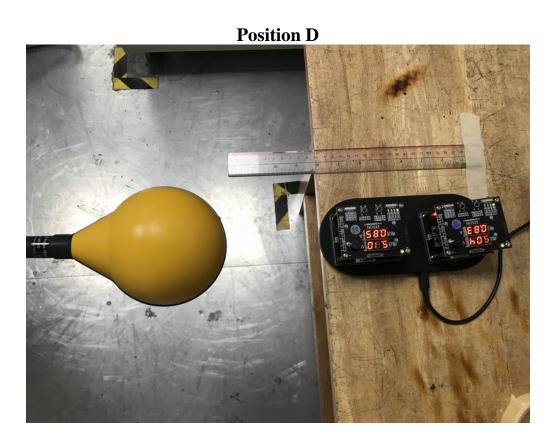
Position B





EST Technology Co., Ltd Report No. ESTE-R2003002 Page 9 of 14

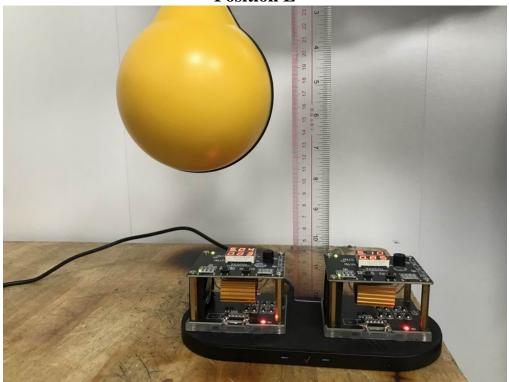




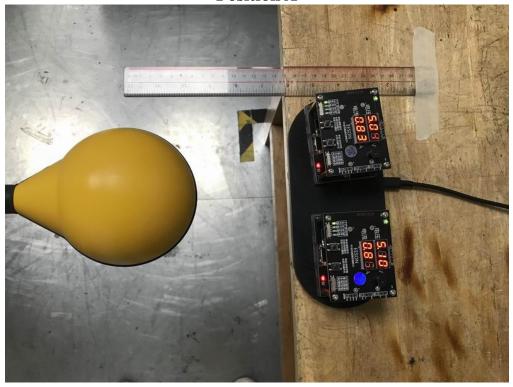


EST Technology Co., Ltd Report No. ESTE-R2003002 Page 10 of 14

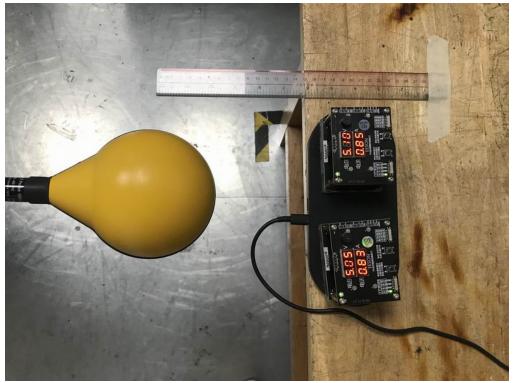




Test setup B
Position A



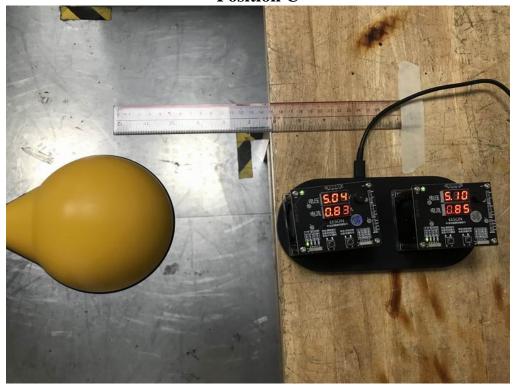




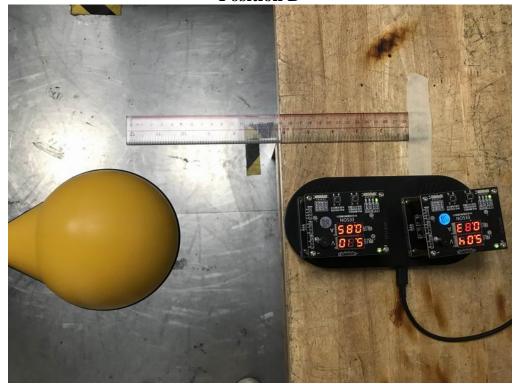


EST Technology Co., Ltd

Position C









EST Technology Co., Ltd Report No. ESTE-R2003002

Position E



End of Test Report



EST Technology Co., Ltd Report No. ESTE-R2003002